Supporting Information

A simple, repeatable and highly stable selfpowered solar-blind photoelectrochemical-type photodetector using amorphous Ga₂O₃ films grown on 3D carbon fiber paper

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Fig. S1. photocurrent density (I_{photo}) of *a*-Ga₂O₃/CFP PEC-PDs with different sputtering time under different 254 nm light intensities. *It is worth noting that* photocurrent density (I_{photo}) was calculated as follows: $I_{photo} = I_{light} - I_{dark}$, where I_{light} and I_{dark} are defined as the current density with or without irradiation.



Fig. S2. SEM morphologies of (a-b) CFP and (c-d) a-Ga₂O₃/CFP photoelectrode. As seen, the CFP is composed of smooth carbon fiber rods with a diameter of ~ 10 µm in staggered stack arrangement. After sputtering a-Ga₂O₃, the metallic luster of CFP disappears, and the surface of the carbon fiber rods is no longer smooth. Moreover, the a-Ga₂O₃ is well wrapped on the CFP, at least for the most part, forming a similar a-Ga₂O₃/CFP core-shell structure.



Fig. S3. (a) The O 1s core level spectrum of the unetched and etched *a*-Ga₂O₃. The etching time is 60 s. It can be seen from the figure that the O₃ (532.0 eV) peak disappeared after etching, indicating that the chemisorbed species on the surface of *a*-Ga₂O₃ was etched away. (b) The O 1s core level spectrum of the etched *a*-Ga₂O₃. Obviously, O1s core level spectrum can be divided into two peaks, corresponding to O₁ and O₂, demonstrating that the etched *a*-Ga₂O₃ still contains a relatively high concentration of oxygen vacancy (V_O) defects.



Fig. S4. (a) The absorption spectrum of a-Ga₂O₃ film grown on c-Al₂O₃ substrate. (b) The absorption spectrum of CFP and a-Ga₂O₃ film grown on CFP (a-Ga₂O₃/CFP). As seen, the a-Ga₂O₃ film grown on c-Al₂O₃ substrate has no obvious absorption in the visible light region (see Fig. S4a), however, it can be seen from Fig. S4b that CFP and a-Ga₂O₃/CFP have obvious absorption in the visible light region.



Fig. S5. The current density as a function of the light irradiation intensity at 0 V. As can be seen that the photocurrent density increases almost linearly with the increase of the light irradiation intensity, indicating that the photocurrent mainly depends on the number of photogenerated carriers under DUV irradiation. The dependence of the photocurrent on the light irradiation intensity is calculated by the power law: $I \propto P^{\alpha}$, where *P* is the light irradiation intensity, and α is the exponent, which demonstrates the response of the photocurrent to the light irradiation intensity. The α obtained by fitting the graph of the photocurrent density change with the light intensity is 0.70. Note that sublinear increase (as α value is <1) in the current density values as the light irradiation intensity increases have been observed.



Fig. S6. The photoresponse curve of the self-powered *a*-Ga₂O₃/CFP PEC-PD. As seen, when the DUV light is turned on, the photocurrent density exhibits a sharp anode peak before the exponential decay, and finally reaches a new steady-state photocurrent. After turning off the DUV light, the cathodic current peak is immediately observed, and then the current density gradually returns to the level reached before turning on the DUV light.